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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/450,351	11/29/1999	ТОМОЕ УАМАМОТО	SHM-00901	7516
26339	7590 11/05/2002			
L -			EXAMI	NER
	.LL & STEWART PLACE, 53 STATE STREI	ET	TSAI, H JEY	
BOSTON, MA	02109		ART UNIT	PAPER NUMBER
			2812	
			DATE MAILED: 11/05/2002	

Please find below and/or attached an Office communication concerning this application or proceeding.

			Otn
	Application No.	Applicant(s)	
Office Action Commons	09/450,351	YAMAMOTO, TOMOE	
Office Action Summary	Examiner	Art Unit	
	H. Jey Tsai	2812	
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet	with the correspondence address	
A SHORTENED STATUTORY PERIOD FOR REPLY THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute, - Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). Status	66(a). In no event, however, may within the statutory minimum of till apply and will expire SIX (6) M cause the application to become	a reply be timely filed hirty (30) days will be considered timely. ONTHS from the mailing date of this commun ABANDONED (35 U.S.C. § 133).	ication.
1) Responsive to communication(s) filed on 27 A	Nugust 2002 .		
2a) This action is FINAL . 2b) Thi	s action is non-final.		
3) Since this application is in condition for allowa closed in accordance with the practice under a Disposition of Claims			erits is
4)⊠ Claim(s) <u>1-11 and 13-36</u> is/are pending in the	application.		
4a) Of the above claim(s) is/are withdray			
5) Claim(s) is/are allowed.		·	
6)⊠ Claim(s) <u>1-11 and 13-36</u> is/are rejected.		,	
7) Claim(s) is/are objected to.			
8) Claim(s) are subject to restriction and/or	r election requirement.		
Application Papers	·		
9)☐ The specification is objected to by the Examine	r.		
10) The drawing(s) filed on is/are: a) accep	ted or b)□ objected to b	y the Examiner.	
Applicant may not request that any objection to the	e drawing(s) be held in abo	eyance. See 37 CFR 1.85(a).	
11) The proposed drawing correction filed on	_is: a)☐ approved b)☐	disapproved by the Examiner.	
If approved, corrected drawings are required in rep	oly to this Office action.		
12)☐ The oath or declaration is objected to by the Ex	aminer.		
Priority under 35 U.S.C. §§ 119 and 120			
13) Acknowledgment is made of a claim for foreign	priority under 35 U.S.C	C. § 119(a)-(d) or (f).	
a) ☐ All b) ☐ Some * c) ☐ None of:			
1. Certified copies of the priority documents	s have been received.		
2. Certified copies of the priority documents	s have been received in	Application No	
Copies of the certified copies of the prior application from the International But See the attached detailed Office action for a list.	reau (PCT Rule 17.2(a)).	е
14) Acknowledgment is made of a claim for domestic	•		lication).
a) The translation of the foreign language pro	visional application has	been received.	,
Attachment(s)	o priority under oo o.o.	33 120 WHM/OF 121.	
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	5) Notice	ew Summary (PTO-413) Paper No(s) of Informal Patent Application (PTO-152	
Information Disclosure Statement(s) (PTO-1449) Paper No(s) S Patent and Trademark Office	6) [_] Other:	·	

Application/Control Number: 09/450,351 Page 2

Art Unit: 2812

Claim Rejections - 35 U.S.C. § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-11 and 13-36 are rejected under 35 U.S.C. 103(a) as being unpatentable over DeBoer et al. 6,146,959 or Huang 6,057,189, in view of Tamaru et al. 6,103,566, or Nishikawa 6,087,261 or Lee et al. 6,010,940, all are previously applied.

The reference(s) teach the features:

DeBoer et al. substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

forming a tantalum oxide dielectric layer 38, fig. 2+, annealing the substrate and forming a CVD TiN directly on the layer 38, see col. 4, lines 31+, or

treating substrate in the chamber with at least one of a gas containing non-reactive NF3 or hydrazine gas and NH_3 to form a layer 40, col. 4, lines 29+,

annealing substrate, and forming a CVD TiN film 42 directly on dielectric layer 38.

Huang substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

Art Unit: 2812

forming a tantalum oxide dielectric layer 36, fig. 2C+, treating substrate with non-reactive nitrogen gas , col. 4, lines 47+,

forming a CVD TiN film 38 over dielectric layer 38.

Tamaru et al. substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

forming a tantalum oxide dielectric layer 5, fig. 4B, and col. 16, lines 7+,

treating substrate in the chamber with at least one of a gas containing non-reactive helium or Ar or N_2 gas and NH_3 , heating the substrate in the NH_3 col. 9, lines 44+.

forming a TiN film over the dielectric layer 5.

Nishikawa substantially discloses a method of forming a capacitor on the semiconductor device, which includes:

forming a tantalum oxide dielectric layer 5, fig. 4B, treating substrate in the chamber with at least one of a gas containing non-reactive NH_3 and helium gases flow, col. 9, lines 1+,

heating the substrate in the NH_3 ambient at about 0.15 torr, fig. 6, col. 9, lines 30+,

forming a TiN film over the dielectric layer 5.

Since, Tamaru, Nishikawa and Lee et al. teach details of forming a CVD TiN. It would have been obvious to one having

Application/Control Number: 09/450,351 Page 4

Art Unit: 2812

ordinary skill in the art at the time the invention was made to have using Tamaru, Nishikawa and Lee et al.'s CVD TiN process to form a TiN film over dielectric layer

Applicant's arguments filed July 12, 2002, 2002 have been fully considered but they are not persuasive. Because DeBoer clearly teaches in col.4, lines 31+, that forming dielectric layer 38, then annealing and forming TiN directly on the layer 39 or forming a dielectric layer 40 on layer 38 then annealing and forming a TiN directly on layer 40. And, Sandhu and Huang clearly teach heating the dielectric layer with non-reactive gas as set forth above.

Any inquiry of a general nature or clerical matters or relating to the status of this application or proceeding should be directed to the Group customer service whose telephone number is (703) 306-3329 and Fax number (703) 306-5515. Group receptionist telephone number 703-308-0956.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to H. Jey Tsai whose telephone number is (703) 308-1374. The examiner can normally be reached on from 7:00 Am to 4:00 Pm., Monday thru Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Niebling can be reached on (703) 308-3325. The fax phone number for this Group is (703) 308-7722.

hjt 11/3/02 Application/Control Number: 09/450,351

Art Unit: 2812

H. Je√ Tsai

Primary Examiner

Patent Examining Group 2800

Page 5